

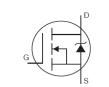
HEXFET[®] Power MOSFET

Features

- Advanced Planar Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications



V _{DSS}	75V
R _{DS(on)} max.	4.5mΩ
D (Silicon Limited)	170A
D (Package Limited)	75A



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
Base part number	Fackage Type	Form Quantit		Orderable Fait Nulliber
AUIRF2907Z	TO-220	Tube	50	AUIRF2907Z

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol Parameter		Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	170	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	120	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	75	A
I _{DM}	Pulsed Drain Current ①	600	
P _D @T _C = 25°C	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
V _{GS} Gate-to-Source Voltage		± 20	V
E _{AS} Single Pulse Avalanche Energy (Thermally Limited) 2		270	
E _{AS} (Tested)	Single Pulse Avalanche Energy Tested Value ⑦	690	- mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	А
E _{AR}	Repetitive Avalanche Energy 6		mJ
TJ	Operating Junction and	-55 to + 175	
T _{STG} Storage Temperature Range			°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ ext{ heta}JC}$	Junction-to-Case ®		0.509	
$R_{ ext{ heta}CS}$	Case-to-Sink, Flat, Greased Surface 🗇	0.50		°C/W
R _{0JA}	Junction-to-Ambient 🗇		62	

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*Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	75		_	V	V _{GS} = 0V, I _D = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.069		V/°C	Reference to 25°C, $I_D = 1mA$
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.5	4.5	mΩ	V _{GS} = 10V, I _D = 75A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	V _{DS} = V _{GS} , I _D = 250μA
gfs	Forward Trans conductance	180			S	V _{DS} = 10V, I _D = 75A
1	Drain-to-Source Leakage Current			20	μA	V _{DS} = 75V, V _{GS} = 0V
I _{DSS}	Drain-to-Source Leakage Current			250	μΑ	V _{DS} =75V,V _{GS} = 0V,T _J =125°C
1	Gate-to-Source Forward Leakage			200	5	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	·		-	-		
Q _g	Total Gate Charge		180	270		I _D = 75A
Q _{gs}	Gate-to-Source Charge		46		nC	V _{DS} = 60V
Q _{gd}	Gate-to-Drain Charge		65]	V _{GS} = 10V ④
t _{d(on)}	Turn-On Delay Time		19			V _{DD} = 38V
t _r	Rise Time		140			I _D = 75A
t _{d(off)}	Turn-Off Delay Time		97		ns	R _G = 2.5Ω
t _f	Fall Time		100			V _{GS} = 10V ④
L _D	Internal Drain Inductance		5.0		nH	Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance		13			from package and center of die contact
C _{iss}	Input Capacitance		7500			V _{GS} = 0V
C _{oss}	Output Capacitance		970			V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		510		pF	f = 1.0MHz, See Fig. 5
C _{oss}	Output Capacitance		3640		рг	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C _{oss}	Output Capacitance		650			$V_{GS} = 0V, V_{DS} = 60V f = 1.0MHz$
C _{oss eff.}	Effective Output Capacitance		1020			$V_{GS} = 0V$, $V_{DS} = 0V$ to $60V$
Diode Chara	acteristics					
	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			75		MOSFET symbol showing the

IS	(Body Diode)			75	^	showing the
I _{SM}	Pulsed Source Current			680	A	integral reverse
ISM	(Body Diode) ①			000		p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_{J} = 25^{\circ}C, I_{S} = 75A, V_{GS} = 0V$ (4)
t _{rr}	Reverse Recovery Time		41	61	ns	T _J = 25°C ,I _F = 75A ,V _{DD} = 38V
Q _{rr}	Reverse Recovery Charge		59	89	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsio	turn-or	n time is	negligi	ble (turn-on is dominated by $L_{S}+L_{D}$)

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

 \odot Limited by T_{Jmax}, starting T_J = 25°C, L = 0.095mH, R_G = 25 Ω , I_{AS} = 75A, V_{GS} =10V. Part not recommended for use above this value.

 $I_{SD} \leq 75A$, di/dt $\leq 340A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 175^{\circ}C$.

④ Pulse width \leq 1.0ms; duty cycle \leq 2%.

⑤ Coss eff. is a fixed capacitance that gives the same charging time as Coss while V_{DS} is rising from 0 to 80% V_{DSS}.

⑥ Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.

 \odot This value determined from sample failure population, starting T_J = 25°C, L = 0.095mH, R_G = 25 Ω , I_{AS} = 75A, V_{GS} =10V.

 R_{θ} is measured at T_J of approximately 90°C. 8

IC-220 device will have an Rth of 0.45°C/W.



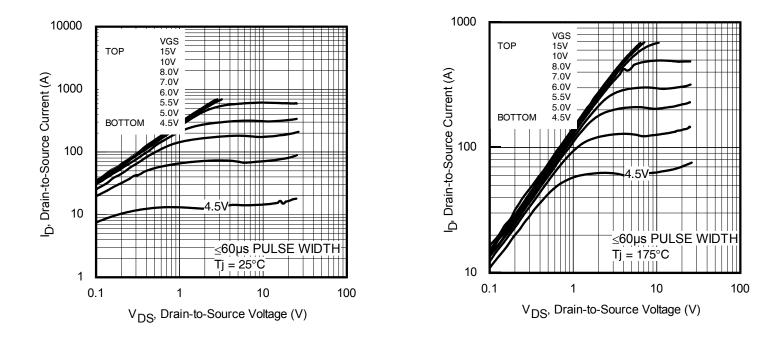
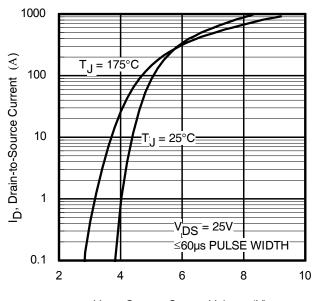


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics



 V_{GS} , Gate-to-Source Voltage (V)

Fig. 3 Typical Transfer Characteristics

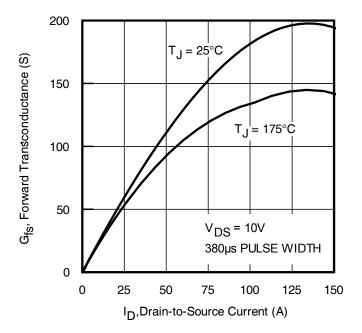


Fig. 4 Typical Forward Transconductance Vs. Drain Current



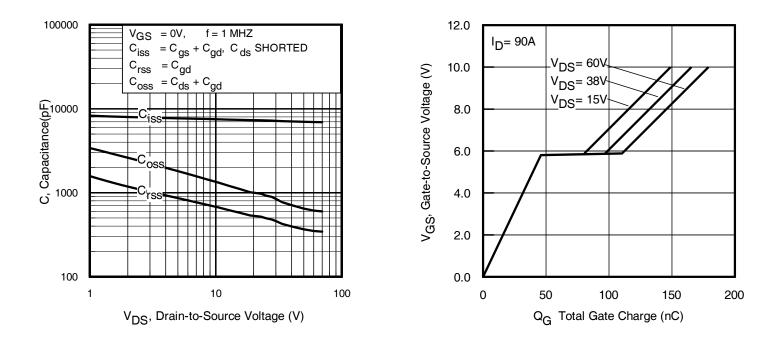


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

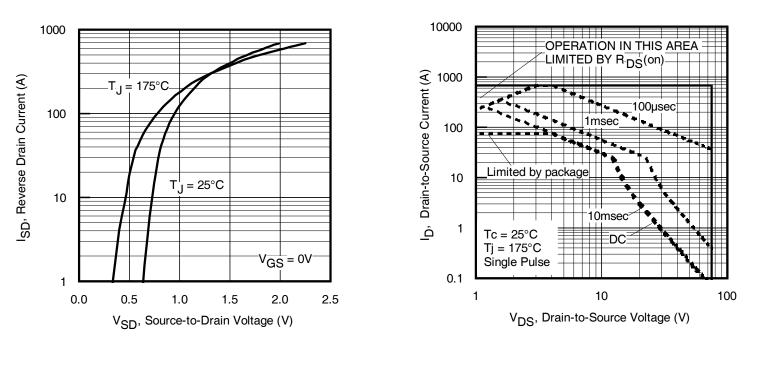


Fig. 7 Typical Source-to-Drain Diode Forward Voltage



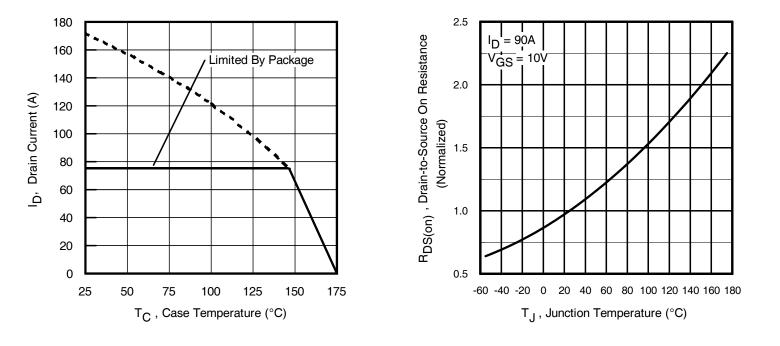


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

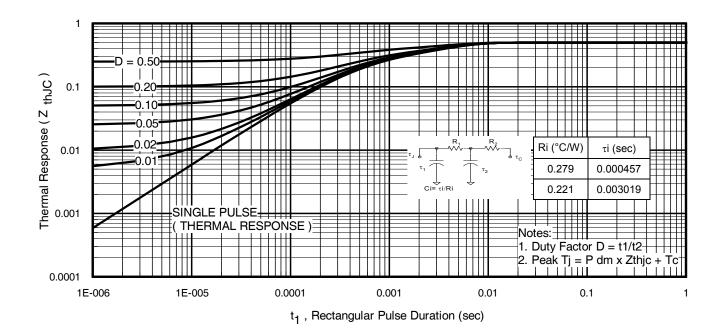


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

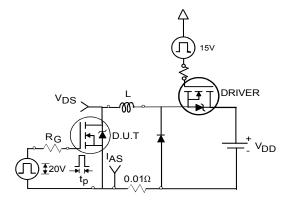


Fig 12a. Unclamped Inductive Test Circuit

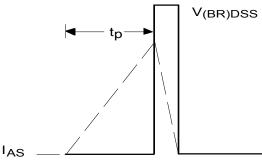
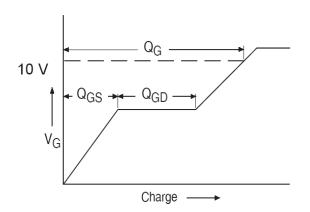
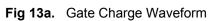


Fig 12b. Unclamped Inductive Waveforms





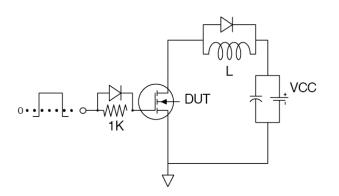


Fig 13b. Gate Charge Test Circuit

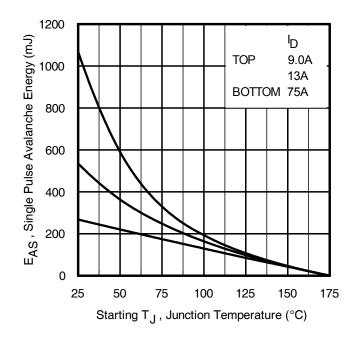


Fig 12c. Maximum Avalanche Energy vs. Drain Current

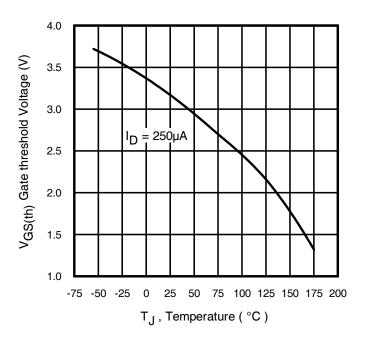
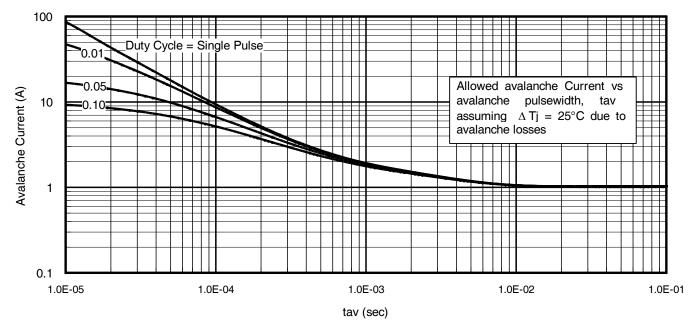


Fig 14. Threshold Voltage vs. Temperature







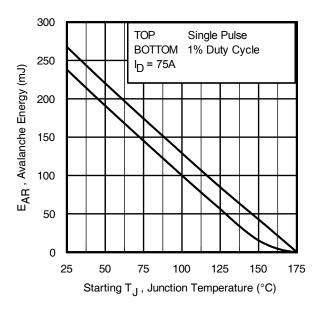


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
 - tav = Average time in avalanche.
 - D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 11)

$$\begin{split} \textbf{P}_{D (ave)} &= 1/2 \text{ (} 1.3 \cdot \textbf{BV} \cdot \textbf{I}_{av} \text{)} = \Delta T / \textbf{Z}_{thJC} \\ \textbf{I}_{av} &= 2 \Delta T / \text{ [} 1.3 \cdot \textbf{BV} \cdot \textbf{Z}_{th} \text{]} \\ \textbf{E}_{AS (AR)} &= \textbf{P}_{D (ave)} \cdot \textbf{t}_{av} \end{split}$$



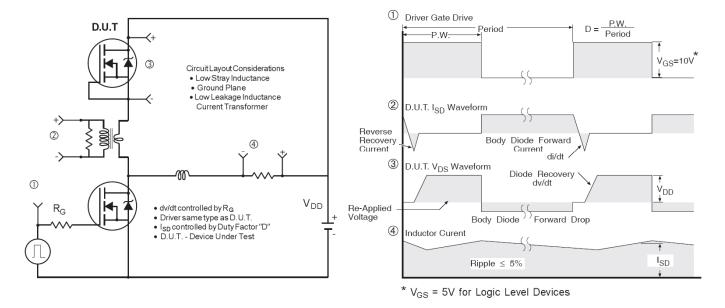
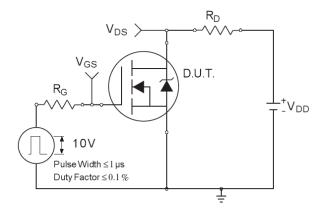
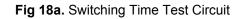


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs





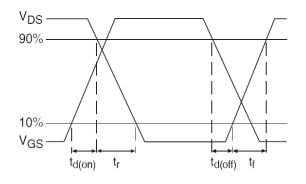
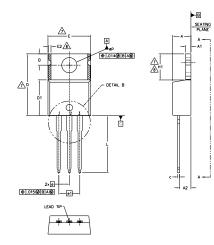
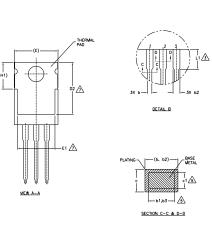


Fig 18b. Switching Time Waveforms



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:	
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- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994. 1.-
- 2.-
- 3 -
- DIMENSIONING AND TOLERAINCING AS PER ASME 114.5 MF 1934. DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS] LEAD DIMENSION AND FINISH UNCONTROLLED IN L1. DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE 4.-MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY. /5.-
- 6.-CONTROLLING DIMENSION : INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1 7. – 8. –
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- UTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE. 9.-

	DIMENSIONS				
SYMBOL	MILLIM	MILLIMETERS INCHES			
	MIN.	MAX.	MIN.	MAX.	NOTES
A	3.56	4.83	.140	.190	
A1	1.14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
с	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
е	2.54	BSC	.100	BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
øР	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS

<u>HEXFET</u> 1.- GATE 2.- DRAIN 3.- SOURCE

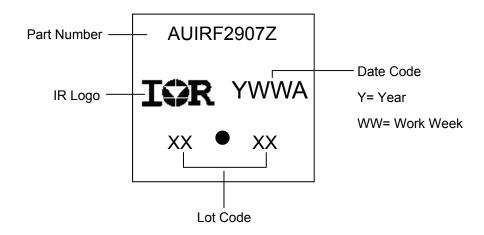
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

1.- ANODE 2.- CATHODE 3.- ANODE

TO-220AB Part Marking Information



TO-220AB package is not recommended for Surface Mount Application.



Qualification Information

		Automotive (per AEC-Q101)				
Qualificatio	n Level	Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture S	ensitivity Level	TO-220AB N/A				
	Machine Model		Class M4 (+/- 425V) [†]			
		AEC-Q101-002				
ESD	Human Dady Madal	Class H2 (+/- 4000V) [†]				
ESD	Human Body Model	AEC-Q101-001				
	Charged Device Medal		Class C4 (+/- 1000V) [†]			
Charged Device Model		AEC-Q101-005				
RoHS Com	pliant	Yes				

† Highest passing voltage.

Revision History

Date	Comments				
9/21/2017	Updated datasheet with corporate template.Corrected typo error on package outline and part marking on page 9.				

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